

**Search Notes**

Application/Control No.

10/740,698

Examiner

Benjamin Huh

Applicant(s)/Patent under  
Reexamination

VARNER ET AL.

Art Unit

3767

**SEARCHED**

Class	Subclass	Date	Examiner
604	890.1, 891.1, 93.01, 521	6/30/2006	BHH
424	427-428	6/30/2006	BHH
424	422	6/30/2006	BHH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/30/2006	BHH